

J666-VB Datasheet

P-Channel 100 V (D-S) MOSFET

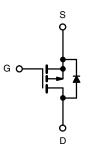
PRODUCT SUMMARY					
V _{DS} (V)	R_{DS(on)} (Ω)	I _D (A)	Q _g (Typ.)		
- 100	0.040 at V _{GS} = - 10 V	- 37	54 nC		
	0.050 at V _{GS} = - 4.5 V	- 32	54 110		

D²PAK (TO-263) G D S

FEATURES

• TrenchFET[®] Power MOSFET





P-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T _A =	= 25 °C, unless othe	erwise noted)		
Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V _{DS}	- 100	V	
Gate-Source Voltage	V _{GS}	± 20	v	
	T _C = 25 °C		- 37	
	T _C = 70 °C		- 29.5	
Continuous Drain Current (T _J = 150 °C) ^b	T _A = 25 °C		- 10 ^{b, c}	
	T _A = 70 °C	1	- 8.2 ^{b, c}	A
Pulsed Drain Current	I _{DM}	- 150	A	
Continuous Courses Current (Diada Conduction)	T _C = 25 °C		- 50 ^a	
Continuous Source Current (Diode Conduction)	T _A = 25 °C	I _S	- 6.75 ^{b, c}	
Avalanche Current	L = 0.1 mH		- 35	
Single Pulse Avalanche Energy		E _{AS}	61	mJ
	T _C = 25 °C		113.6	
Maujauna Davias Diasinatian	T _C = 70 °C	P _D	72.7	w
Maximum Power Dissipation	T _A = 25 °C		6.9 ^{b, c}	vv
	T _A = 70 °C	1 [4.4 ^{b, c}	
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Limit	Unit		
Junction-to-Ambient	PCB Mount (TO-263) ^c R _{thJA} 40		40	°C/W		
Junction-to-Case (Drain)		R _{thJC}	2.1	0/11		

Notes:

a. Package limited.

b. Surface mounted on 1" x 1" FR4 board.

c. t = 10 s.

SPECIFICATIONS ($T_J = 25 \ ^{\circ}C$,			Min	True	Max	Unit	
Parameter Static	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = - 250 μA	- 100	1		V	
V _{DS} Temperature Coefficient		V _{GS} = 0 V, 1 _D = - 230 μA	- 100	100		v	
-	$\Delta V_{DS}/T_J$	$l_{\rm D} = -250 \mu {\rm A}$		- 109		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	V _{DS} = V _{GS} , I _D = - 250 μA		5.9			
Gate-Source Threshold Voltage	V _{GS(th)}		- 1		- 3	V	
Gate-Source Leakage	IGSS	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA	
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = -100 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$				-1 μΑ	
		$V_{DS} = -100 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 55 \text{ °C}$			- 10	· · · · · · · · · · · · · · · · · · ·	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = -10 \text{ V}$	- 40			A	
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = - 10 V, I _D = - 9.2 A		0.040		Ω	
	DO(01)	V _{GS} = - 4.5 V, I _D = - 7.7 A		0.050			
Forward Transconductance ^a	9 _{fs}	V _{DS} = - 15 V, I _D = - 9.2 A		38		S	
Dynamic ^b							
Input Capacitance	C _{iss}	V _{DS} = - 50 V, V _{GS} = 0 V, f = 1 MHz		3800		pF	
Output Capacitance	C _{oss}			185			
Reverse Transfer Capacitance	C _{rss}			135			
Table Oats Observe		$V_{DS} = -50$ V, $V_{GS} = -10$ V, $I_{D} = -9.2$ A		106	160	nC	
Total Gate Charge	Qg	Q_g		54	81		
Gate-Source Charge	Q _{gs}	V_{DS} = - 50 V, V_{GS} = - 4.5 V, I_{D} = - 9.2 A		14			
Gate-Drain Charge	Q _{gd}			26			
Gate Resistance	R _g	f = 1 MHz		4		Ω	
Turn-On Delay Time	t _{d(on)}			15	25	- ns	
Rise Time	t _r	$V_{DD} = -50 \text{ V}, \text{ R}_{\text{I}} = 6.5 \Omega$		20	30		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong$ - 7.7 A, V_{GEN} = - 10 V, R_g = 1 Ω		110	165		
Fall Time	t _f			100	150		
Turn-On Delay Time	t _{d(on)}			42	65		
Rise Time	t _r	V_{DD} = - 50 V, R _L = 6.5 Ω		160	240	- ns	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong -7.7 \text{ A}, V_{\text{GEN}} = -4.5 \text{ V}, R_q = 1 \Omega$		100	150		
Fall Time	t _f			100	150		
Drain-Source Body Diode Characteristic						1	
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			- 50		
Pulse Diode Forward Current ^a	I _{SM}	-			- 40	A	
Body Diode Voltage	V _{SD}	I _S = - 7.7 A		- 0.8	- 1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			60	90	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	1		150	225	nC	
Reverse Recovery Fall Time	t _a	I _F = - 7.7 A, dl/dt = 100 A/μs, T _J = 25 °C		46		ns	
Reverse Recovery Rise Time	t _b	4		14			
Notes:	۳D			14	l		

Notes:

a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %.

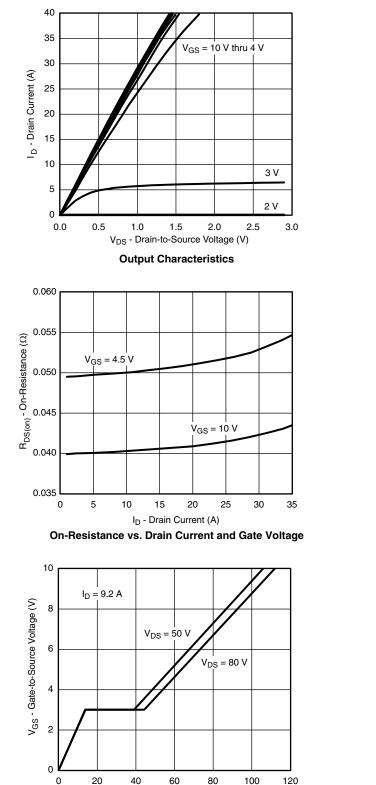
b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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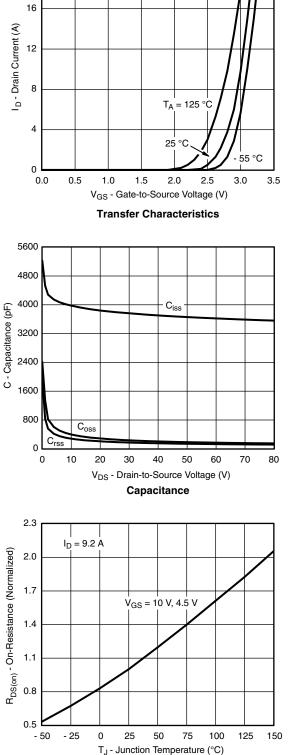


Q_q - Total Gate Charge (nC)

Gate Charge

TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

20



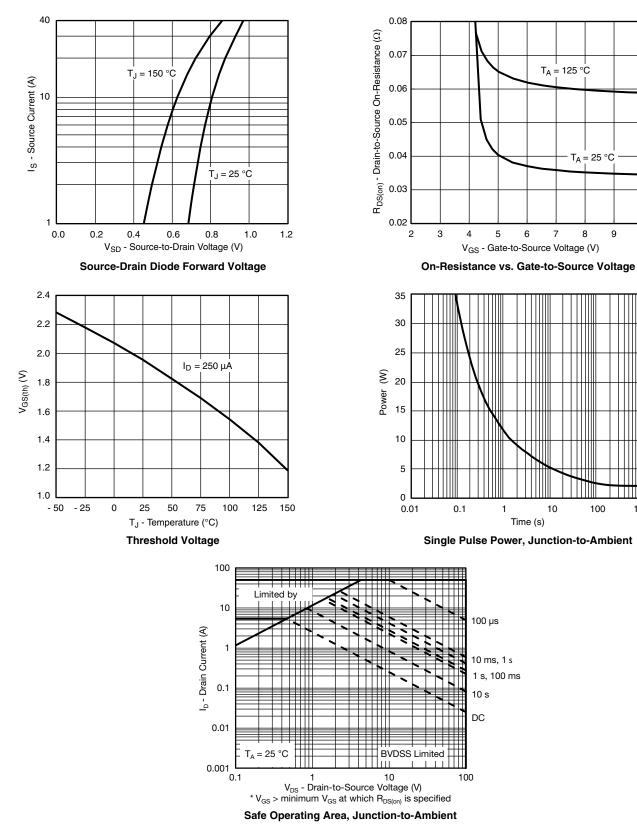
On-Resistance vs. Junction Temperature



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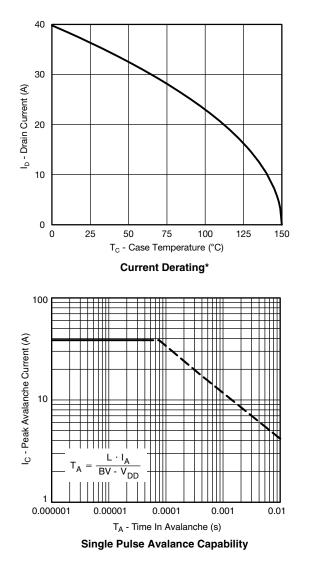
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1000

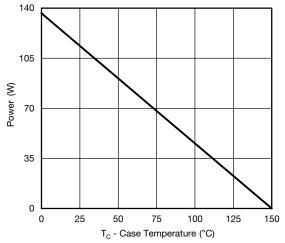


TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)





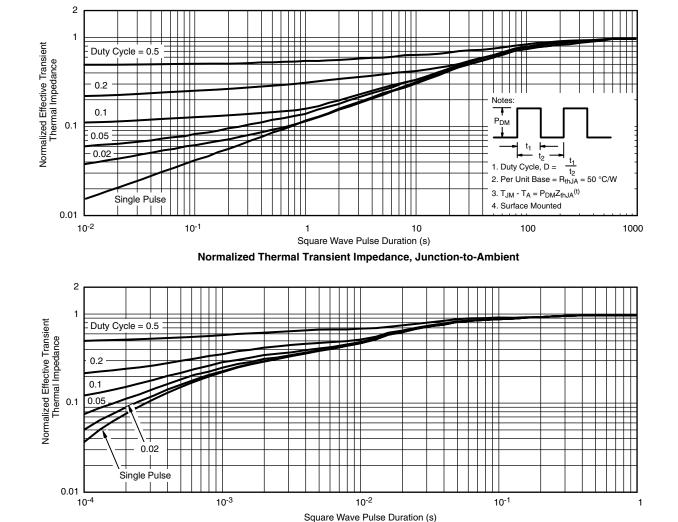
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



Single Pulse Power, Junction-to-Ambient

* The power dissipation P_D is based on $T_{J(max.)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



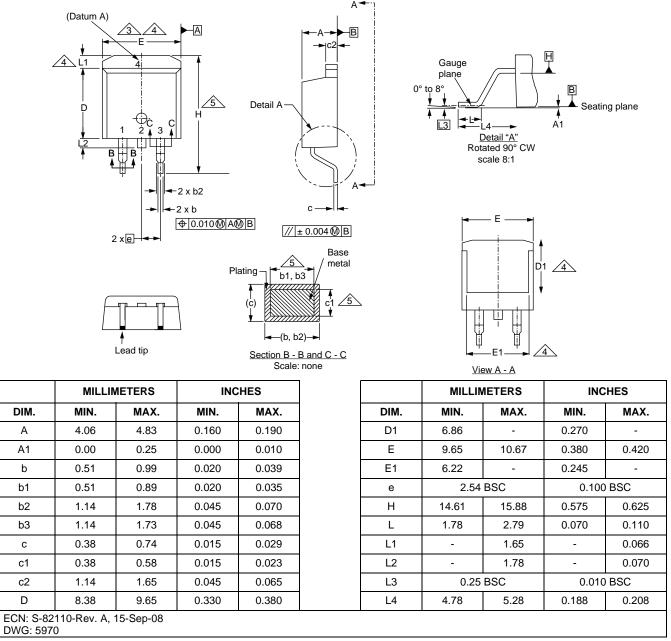


TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

Normalized Thermal Transient Impedance, Junction-to-Case



TO-263AB (HIGH VOLTAGE)



Notes

1. Dimensioning and tolerancing per ASME Y14.5M-1994.

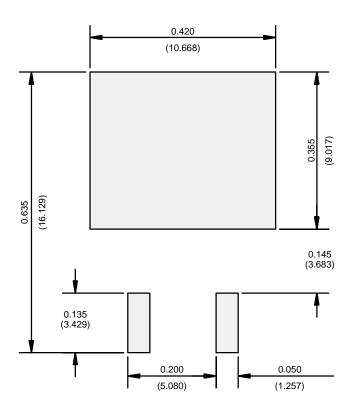
2. Dimensions are shown in millimeters (inches).

3. Dimension D and E do not include mold flash. Mold flash shall not exceed 0.127 mm (0.005") per side. These dimensions are measured at the outmost extremes of the plastic body at datum A.

- 4. Thermal PAD contour optional within dimension E, L1, D1 and E1.
- 5. Dimension b1 and c1 apply to base metal only.
- 6. Datum A and B to be determined at datum plane H.
- 7. Outline conforms to JEDEC outline to TO-263AB.



RECOMMENDED MINIMUM PADS FOR D²PAK: 3-Lead



Recommended Minimum Pads Dimensions in Inches/(mm)



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